

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Shunpei Yamazaki et al.      Art Unit : 2629  
 Serial No. : 09/504,235      Examiner : David L. Lewis  
 Filed : February 15, 2000      Conf. No. : 7610  
 Title : METHOD OF MANUFACTURING A SEMICONDUCTOR DEVICE

**MAIL STOP RCE**

Commissioner for Patents  
 P.O. Box 1450  
 Alexandria, VA 22313-1450

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INFORMATION DISCLOSURE STATEMENT

Applicants request consideration of the reference listed on the attached PTO-1449 form.

A copy of the listed U.S. patent can be provided upon request.

This filing is being made with the filing of a Request for Continued Examination. No fee is required.

Respectfully submitted,

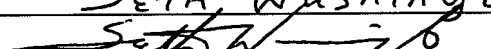
Date: 6/18/07

  
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**CERTIFICATE OF HANDCARRY**

I hereby certify that this correspondence is being delivered by hand on the date indicated below and is addressed to the U.S. Patent and Trademark Office, Office of Petitions, 600 Dulany Street, Madison West, 7C49, Alexandria, VA 22313.

Name (Print/Type)	Seth Washington		
Signature		Date	June 18, 2007

Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 07977-008004	Application No. 09/504,235
<b>Information Disclosure Statement by Applicant</b> (Use several sheets if necessary) (37 CFR §1.98(b))		Applicant Shunpei Yamazaki et al.	
		Filing Date February 15, 2000	Group Art Unit 2629

U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	5,475,514	12/12/1995	Salerno et al.			08/11/1994
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
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Foreign Patent Documents or Published Foreign Patent Applications								
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	AL							
	AM							
	AN							
	AO							
	AP							

Other Documents (include Author, Title, Date, and Place of Publication)		
Examiner Initial	Desig. ID	Document
	AQ	
	AR	
	AS	
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Examiner Signature	Date Considered
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	